

## TRADEMARK ASSIGNMENT COVER SHEET

Electronic Version v1.1  
Stylesheet Version v1.2

ETAS ID: TM489253

<b>SUBMISSION TYPE:</b>	NEW ASSIGNMENT		
<b>NATURE OF CONVEYANCE:</b>	RELEASE OF SECURITY INTEREST		
<b>CONVEYING PARTY DATA</b>			
<b>Name</b>	<b>Formerly</b>	<b>Execution Date</b>	<b>Entity Type</b>
Comerica Bank		09/04/2018	N.A.: MICHIGAN
<b>RECEIVING PARTY DATA</b>			
<b>Name:</b>	Luxtron Corporation		
<b>Street Address:</b>	3301 Leonard Court		
<b>City:</b>	Santa Clara		
<b>State/Country:</b>	CALIFORNIA		
<b>Postal Code:</b>	95054		
<b>Entity Type:</b>	Corporation: DELAWARE		
<b>PROPERTY NUMBERS Total: 2</b>			
<b>Property Type</b>	<b>Number</b>	<b>Word Mark</b>	
<b>Serial Number:</b>	78656476	ILLUMA	
<b>Serial Number:</b>	75264397	OPTIMA 9000	
<b>CORRESPONDENCE DATA</b>			
<b>Fax Number:</b>	4142974900		
<i>Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.</i>			
<b>Phone:</b>	414-271-2400		
<b>Email:</b>	ipdocketing@foley.com, sfelde@foley.com		
<b>Correspondent Name:</b>	Christopher M. King		
<b>Address Line 1:</b>	3000 K Street, N.W. Suite 600		
<b>Address Line 2:</b>	Foley & Lardner LLP		
<b>Address Line 4:</b>	Washington, D.C. 20007-5109		
<b>ATTORNEY DOCKET NUMBER:</b>	115859-0117		
<b>NAME OF SUBMITTER:</b>	Christopher M. King		
<b>SIGNATURE:</b>	/Christopher M. King/		
<b>DATE SIGNED:</b>	09/10/2018		
<b>Total Attachments: 9</b>			
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RELEASE OF SECURITY INTEREST

This Release of Security Interest is made as of September 4, 2018, by COMERICA BANK ("Bank") in favor of LUMASENSE TECHNOLOGIES HOLDINGS, INC., a Delaware corporation, as successor in interest to LUMASENSE TECHNOLOGIES, INC. ("Company"), LUXTRON CORPORATION (the "Guarantor") with its principal place of business located at 3301 Leonard Court, Santa Clara, California 95054.

Recital

WHEREAS Company and Guarantor granted to Bank a security interest in the copyrights, patents and trademarks described on Exhibits A, B and C attached hereto, respectively (collectively, the "Intellectual Property") under an Intellectual Property Security Agreement dated as of April 12, 2007 (the "Security Agreement"), and recorded with the US Library of Congress Copyright Office and the US Patent and Trademark Office as set forth on Exhibits A, B and C.

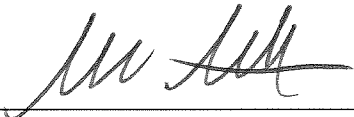
WHEREAS Company and Guarantor has no outstanding obligations to Bank under the terms of the Security Agreement, Bank agrees to release its security interest in the Intellectual Property.

Agreement

Now therefore, Bank agrees that it terminates and releases its security interest in the Intellectual Property and reassigns to Company, without warranty or recourse, all interest of Bank in the Intellectual Property.

BANK:

COMERICA BANK



Name: Robert Shutt

Title: Senior Vice President

333 W. Santa Clara St., 12<sup>th</sup> Floor  
San Jose, CA 95113

**EXHIBIT A**

**Copyrights**

<u>Description</u>	<u>Registration Number</u>	<u>Registration Date</u>
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NONE

**EXHIBIT B**

**Patents**

<b>Description</b>	<b>Patent / Application Number</b>	<b>Issue / Application Date</b>
1. Emissivity corrected radiation pyrometer integrated with a reflectometer and roughness sensor for measuring true surface temperature at a distance from the sample	10/616,254	7/8/2003
2. System and Method for Monitoring Temperature During electrosurgery or Laser Therapy	11/499,530	8/4/2006
3. In Situ Optical Surface Temperature Measuring Techniques and Devices	11/361,543	2/24/2006
4. Utility Transformer Measurement Probe	11/337,641	1/23/2006
5. Devices, Systems and Methods for Determining Temperature and/or Optical Characteristics of a Substrate	11/241,579	9/30/2005
6. Endpoint Detection Technique Using Signal Slope De	066350	5/1/94
7. In Situ Technique for Monitoring and Controlling a	099818	5/7/99
8. Optical Sensors For Detecting Physical Parameters	144630	7/12/89
9. Optical Sensors For Detecting Physical Parameters	161671	6/27/90
10. Fiber Optic Sensor With a Fluorescing Substance	174506	10/23/91
11. Optical Techniques For Measuring Layer Thicknesses And Other Surface Character	199054	2/29/00
12. Optical Temperature Measurement Techniques	203992	2/17/93
13. Sensors For Detecting Electromagnetic Parameters U	345142	7/28/93
14. An Electro-Optical Board Assembly For Measuring The Temperature Of An Object Surface From Infra-Red Emissions Thereof, Including An Automatic Gain Control Therefore	0347727	9/22/95
15. Fiberoptic Techniques For Measuring The Magnitude	0390651	5/1/96
16. Three-Parameter Optical Fiber Sensor And System	0392897	12/29/93
17. Modular Luminescence-Based Measuring System Using Fast Digital Signal Processing	0560903	1/7/98
18. An Electro-Optical Board Assembly For Measuring The Temperature Of An Object Surface From Infra-Red Emissions Thereof, Including An Automatic Gain Control Therefore	0783672	9/22/95
19. Optical Sensors For Detecting Physical Parameters	1,251,057	3/14/89
20. Non-Contact Optical Techniques For Measuring Surface	1,263,922	12/19/89
21. Optical Temperature Measurement Techniques	1,264,236	1/9/90
22. Fiberoptic Sensing of Temperature and/or Other Phy	1,292,368	11/26/91
23. Programmable Calibrated Optical Fiber Thermometer	1916872	3/23/95
24. Optical Temperature Measurement Techniques	2035740	3/28/96
25. Three-Parameter Optical Fiber Sensor And System	3040103	3/3/00
26. Optical Fiber Thermometer	3192161	5/25/01
27. Modular Luminescence-Based Measuring System Using Fast Digital Signal Processing	3249820	11/9/01
28. Endpoint Detection Technique Using Signal Slope De	3,375,338	11/28/98
29. Hi-Temp Black Body Tip Sensor	4,576,486	
30. Multi-Channel Fiber Optic Connector	4,712,864	5/2/85
31. Blackbody Radiation Sensing Optical Fiber Thermometer	4,750,139	8/29/85
32. Optical Temperature Measurement Techniques	4,789,992	3/19/87
33. Method Of Making A Fiberoptic Sensor Of A Microwave	4,816,634	10/23/87
34. Method and Apparatus for Determining Temperature in Blackbody Radiation Sensing System	4,845,647	1/24/85
35. Optical System Using a Luminescent Material Sensor	4,859,079	8/4/88
36. Fiberoptic Sensing of Temperature and/or Other Physical parameters	4,883,354	3/4/88

37. Sensors For Detecting Electromagnetic Parameters Utilizing Resonating Elements	4,897,541	6/2/88
38. Three-Parameter Optical Fiber Sensor And System	4,986,671	4/12/89
39. Fiberoptic Sensing of Temperature and/or Other Physical parameters	4,988,212	8/22/89
40. Method And Apparatus For Monitoring Particles Using	5012119	4/29/87
41. Dew point measuring apparatus installation system	5,024,532	
42. Optical Fiber Thermometer	5052214	10/1/91
43. Light Collection Method And apparatus	5064269	11/11/87
44. Knock detector using optical fiber thermometer	5,099,681	11/11/87
45. Modular Luminescence-Based Measuring System Using Fast Digital Signal Processing	5107445	12/4/90
46. Method Of Making A Fiberoptic Sensor Of A Microwave	5,109,595	4/1/91
47. Fiberoptic Techniques For Measuring The Magnitude	5,110,216	1/30/90
48. Temperature Measurement With Combined Photo-Luminescent and Blackbody sensing technique	5112137	5/12/92
49. Apparatus and Method for Monitoring Radiant Energy	5,138,149	9/5/90
50. Non-Contact Techniques For Measuring Temperature Of Radiation-Heated Objects	5,154,512	4/10/90
51. Techniques For Measuring The Thickness Of A Film F	5,166,080	4/29/91
52. Through The Wafer Optical Transmission Sensor	5,166,525	2/11/91
53. Temperature Measurement With Combined Photo-Luminescent and Blackbody sensing technique	5,183,338	12/13/91
54. Method Of Endpoint Detection And Structure Therefo	5,190,614	9/5/90
55. Method For Control Of Photoresist Develop Processe	5,196,285	3/23/93
56. Interference Removal	5,208,644	5/4/93
57. Autocalibrating dual sensor non-contact temperature measuring device	5,216,625	
58. Method For Control Of Photoresist Develop Processes	5,292,605	3/8/94
59. Autocalibrating dual sensor non-contact temperature measuring device	5,294,200	3/8/94
60. Luminescent Decay Time Measurements By Use Of A CCD Camera	5,304,809	9/15/92
61. Endpoint and Uniformity Determinations in Material Layer Processing Through Monitoring Multiple Surface Regions Across The Layer	5,308,447	6/9/92
62. Non-Contact Optical Techniques For Measuring Surface Conditions	5,310,260	12/28/92
63. Non-Contact Techniques For Measuring Temperature Of Radiation-Heated Objects	5,318,362	9/11/92
64. Modular Luminescence-Based Measuring System Using Fast Digital Signal Processing	5,351,268	10/8/91
65. Processing Endpoint Detecting Technique and Detect	5,362,969	4/23/93
66. Thermally Fused Composite Ceramic Blackbody Temper	5,364,186	4/28/92
67. Measuring System Employing A Luminescent Sensor An	5,414,266	6/11/93
68. Interference Removal	5,414,504	2/19/93
69. Autocalibrating non-contact temperature measuring technique employing dual recessed heat flow sensors	5,464,284	
70. Apparatus and Method for Measuring Temperatures at a Plurality of locations using luminescent-type temperature	5,470,155	6/11/93
71. Non-Contact Optical Techniques For Measuring Surface	5,490,728	1/12/94
72. Optical Techniques Of Measuring Endpoint During Th	5,499,733	9/16/93
73. Temperature Measuring System Having Improved Signals	5,600,147	6/6/95
74. Optical Techniques Of Measuring Endpoint During The Process Of Material Layers In An Optically Hostile Environment	5,695,660	3/14/96
75. An Electro-Optical Board Assembly For Measuring The Temperature Of An Object Surface From Infra-Red Emissions Thereof, Including An Automatic Gain Control Therefore	5,717,608	9/26/94
76. Non-Contact Optical Techniques For Measuring Surface Conditions	5,769,540	1/12/94
77. Interference Removal	5,786,886	5/8/95

78. Method and apparatus for measuring atomic vapor density in deposition systems	5,880,823	6/10/1994
79. Optical Techniques Of Measuring Endpoint During Th	5,891,352	6/11/97
80. An Electro-Optical Board Assembly For Measuring The Temperature Of An Object Surface From Infra-Red Emissions Thereof, Including An Automatic Gain Control Therefore	5,897,610	9/26/97
81. Interference Removal	5,946,082	6/16/98
82. In Situ Technique for Monitoring and Controlling a	6,010,538	1/11/96
83. Signal Processing For In Situ Monitoring of the Fo	6,028,669	7/23/97
84. Optical Techniques of Measuring Endpoint During th	6,077,452	4/14/99
85. Optical Techniques of Measuring Endpoint During th	6,110,752	8/27/97
86. Polarization Interferometer Spectrometer with Rotatable Birefringent Element	6,222,632	4/24/01
87. Liquid Etch Endpoint Detection and Process Metrology	6,406,641	6/17/97
88. Optical Techniques of Measuring Endpoint During th	6,413,147	7/1/98
89. Optical Techniques Of Measuring Endpoint During Th	6,426,232	6/15/98
90. Optical Technique for Measuring Layer Thicknesses and other surface characteristics of objects such as semiconductor wafers	6,570,662	5/24/1999
91. In Situ Optical Surface Temperature Measuring Techniques and Devices	6,572,265	4/20/01
92. Optical Technique for Measuring Layer Thicknesses and other surface characteristics of objects such as semiconductor wafers	6,654,132	5/24/00
93. Optical Technique for Measuring Layer Thicknesses and other surface characteristics of objects such as semiconductor wafers	6,934,040	9/26/2003
94. Optical Technique for Measuring Layer Thicknesses and other surface characteristics of objects such as semiconductor wafers	7,042,581	12/15/2004
95. In Situ Optical Surface Temperature Measuring Techniques and Devices	7,080,940	5/5/2004
96. Emissivity corrected radiation pyrometer integrated with a reflectometer and roughness sensor for measuring true surface temperature at a distance from the sample	20030021835	7/11/2003
97. In situ optical surface temperature measuring techniques and devices	20040258130	12/23/04
98. Optical techniques for measuring layer thicknesses and other surface characteristics of objects such as semiconductor wafers	20050105103	5/19/05
99. In situ optical surface temperature measuring techniques and devices	20060140248	6/29/06
100. Method for adapting an existing thermal imaging device	7348562	3/25/08
101. Respiratory gas analyzer	5464982	11/7/95
102. Sensor support subassembly	5582797	12/10/96
103. An electro-optical board assembly for measuring the temperature of an object surface from infra-red emissions	5717608	2/10/98
104. Non-contact optical techniques for measuring surface conditions	5769540	6/23/98
105. Interference removal	5786886	7/28/98
106. Novel multiple-gas NDIR analyzer	5811812	9/22/98
107. Electro optical board assembly for measuring the temperature of an object surface from infra red emissions thereof including an automatic gain control therefore	5897610	4/27/99

108. In situ technique for monitoring and controlling a process of chemical-mechanical-polishing via a radiative	6010538	1/4/00
109. Signal processing for in situ monitoring of the formation or removal of a transparent layer	6028669	2/22/00
110. Polarization interferometer spectrometer with rotatable birefringent element	6222632	4/24/01
111. Liquid etch endpoint detection and process metrology	6406641	6/18/02
112. Infrared spectrophotometer employing sweep	6528791	3/4/03
113. Optical techniques for measuring layer thickness and other surface characteristics of objects such as	6570662	5/27/03
114. In situ optical surface temperature measuring technique	6572265	6/3/03
115. Optical technique for measuring layer thicknesses and other surface characteristics of objects such as	6654132	11/25/03
116. Thermal imaging combination and method	6798587	9/28/04
117. Respiratory gas analyzer	6818895	11/16/04
118. Optical technique for measuring layer thicknesses and other surface characteristics of objects such as	6934040	8/23/05
119. Optical technique for measuring layer thicknesses and other surface characteristics of objects such as	7042581	5/9/06
120. In situ optical surface temperature measuring technique	7080940	7/25/06
121. Method for adapting an existing thermal imaging	7348562	3/25/08
122. In situ optical surface temperature measuring technique	7374335	5/20/08
123. System and method for monitoring asset health by dissolved gas measurement	14001947	8/28/13
124. Respiratory gas analyzer	5464982	11/7/95
125. Sensor support subassembly	5582797	12/10/96
126. An electro-optical board assembly for measuring the temperature of an object surface from	5717608	2/10/98
127. Non-contact optical techniques for measuring surface conditions	5769540	6/23/98
128. Interference removal	5786886	7/28/98
129. Novel multiple-gas NDIR analyzer	5811812	9/22/98
130. Electro optical board assembly for measuring the temperature of an object surface from infra red	5897610	4/27/99
131. In situ technique for monitoring and controlling a process of chemical-mechanical-polishing via a	6010538	1/4/00
132. Signal processing for in situ monitoring of the formation or removal of a transparent layer	6028669	2/22/00
133. Polarization interferometer spectrometer with rotatable birefringent element	6222632	4/24/01



134. Liquid etch endpoint detection and process metrology	6406641	6/18/02
135. Infrared spectrophotometer employing sweep diffraction grating	6528791	3/4/03
136. Optical techniques for measuring layer thickness and other surface characteristics of objects	6570662	5/27/03
137. In situ optical surface temperature measuring technique and devices	6572265	6/3/03
138. Optical technique for measuring layer thicknesses and other surface characteristics of	6654132	11/25/03
139. Thermal imaging combination and method	6798587	9/28/04
140. Respiratory gas analyzer	6818895	11/16/04
141. Optical technique for measuring layer thicknesses and other surface characteristics of	6934040	8/23/05
142. Optical technique for measuring layer thicknesses and other surface characteristics of	7042581	5/9/06
143. In situ optical surface temperature measuring technique and devices	7080940	7/25/06
144. Method for adapting an existing thermal imaging device	7348562	3/25/08
145. In situ optical surface temperature measuring technique and devices	7374335	5/20/08
146. System and method for monitoring asset health by dissolved gas measurement	14001947	8/28/13

Lender's security interest recorded against some or all of the items at the US Patent and Trademark Office at Reel and Frame Number 019224/0843, at Reel and Frame Number 027920/0637, at Reel and Frame Number 033106/0277, and at Reel/Frame Number 043682/0236.

**EXHIBIT A****Trademarks**

<b>Description</b>	<b>Patent / Application Number</b>	<b>Issue / Application Date</b>
1. ILLUMA	78656476	6/22/2005
2. THERMASSET	78306554	9/29/2003
3. OPTIMA 90000	75264397	5/25/1999
4. ACCUFIBER	74090171	8/21/1990
5. FLUOROPTIC	73616762	8/26/1986
6. LUXTRON	73616723	8/26/1986
7. FOCAL POINT	77138448	3/23/07
8. LumaSense Technologies	85070950	6/24/10
9. LUMASHIELD	85170526	11/05/10
10. LUMASMART	77883898	12/2/09
11. FOCAL POINT	77138448	3/23/07
12. SPYGLASS	76437455	8/5/02
13. MIKRON	72377173	11/25/70
14. THERMASSET	78306554	9/29/03
15. ACCUFIBER	74090171	8/21/90
16. FLUOROPTIC	73616762	8/26/86
17. LUXTRON	73616723	8/26/86
18. LUMASENSE	86009637	7/13/13
19. LumaSMART iCore	86005491	7/9/13
20. impac	86005419	7/9/13
21. INNOVA	86004643	7/8/13
22. SmartDGA	86004595	7/8/13
23. DGA Viewer	86004547	7/8/13
24. SmartDGA Go	86004525	7/8/13
25. EZHub	86004499	7/8/13
26. Design	86004439	7/8/13
27. SmartDGA Guide	86004413	7/8/13
28. SmartDGA Gauge	86004383	7/8/13
29. SmartDGA Guard	86004319	7/8/13
30. SmartDGA	85641484	6/1/12

31. SmartDGA Guide	87023634	5/3/16
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Lender's security interest recorded against some or all of the items at the US Patent and Trademark Office at Reel and Frame Number 019224/0843, at Reel and Frame Number 027920/0637, at Reel and Frame Number 033106/0277, and at Reel/Frame Number 043682/0236.